

		PATENT DATE		PATENT NUMBER			
SERIAL NUMBER 08/811,742		FILED DATE 03/08/97	CLASS 437 438	SUBCLASS 52	GROUP ART UNIT 1114 3523		EXAMINER KING, S.
APPLICANT HONGYONG ZHANG, YAMATO-SHI, JAPAN; TORU TAKAYAMA, YOKOHAMA-SHI, JAPAN; YASUHIKO TAKEMURA, TASUTI-SHI, JAPAN; AKIHARU MIYANAGA, HADANO-SHI, JAPAN.							
CONTINUATING DATA VERIFIED THIS APPN IS A CON OF 08/462,742 06/05/95 WHICH IS A DIV OF 08/248,220 05/24/94 PAT 5,604,360							
FOREIGN/FTI APPLICATIONS VERIFIED JAPAN 05/26/93							

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Foreign priority claimed as USC 119 conditions met		<input checked="" type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	AS FILED	STATE OR COUNTRY JPN	SHEETS DRWGS. 7	TOTAL CLAIMS 25	INDEP. CLAIMS 9	FILING FEE RECEIVED \$1,360.00	ATTORNEY'S DOCKET NO. 0756-1641
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SEMICONDUCTOR DEVICE AND FABRICATION METHOD OF THE SAME									
U.S. DEPT. OF COMM / PAT. & TM PTO-436 (Rev. 12-85)									

SEMICONDUCTOR DEVICE AND FABRICATION METHOD OF THE SAME

U.S. DEPT. OF COMM./PAT. & TM PTO-436L (Rev. 12-94)

Assistant Examiner		Total Claims	
		1	
Primary Examiner		DRAWINGS	
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